**Particle quantification by size, shape, distribution;**
**Advanced particle morphology studies;**
**Advanced classification by elemental composition and material characterization to locate the root cause of contamination.**

**Electron Microscopy Workflow**

<table>
<thead>
<tr>
<th>Hardware</th>
<th>Software</th>
<th>Report</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>ZEISS EVO</strong></td>
<td></td>
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<tr>
<td>Particle size ≥ 20 nm</td>
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<tr>
<td><strong>ZEISS Sigma</strong></td>
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<tr>
<td>Particle size ≥ 20 nm</td>
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</tbody>
</table>

**ZEISS Technical Cleanliness Analysis**

- Quantification & basic classification
- One-scan technology: only one filter scan is needed to acquire both brightfield and crossed polarization image information;
- Particle quantification by size, shape, distribution;
- Particle qualification by metallic shiny, non-shiny, fibers;
- Particle height measurement (Axioskop 7, Axio Imager 2)**;
- Oil cleanliness analysis (Axio Imager 2).

**Light Microscopy Workflow**

<table>
<thead>
<tr>
<th>Hardware</th>
<th>Software</th>
<th>Report</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>ZEISS SteREO Discovery.V8</strong></td>
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<tr>
<td>Particle size ≥ 15 μm</td>
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<tr>
<td><strong>ZEISS Axioskop 7</strong></td>
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<tr>
<td>Particle size ≥ 50 μm</td>
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<tr>
<td><strong>ZEISS Axio Zoom.V16</strong></td>
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<tr>
<td>Particle size ≥ 5 μm</td>
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<tr>
<td><strong>ZEISS Axio Imager 2</strong></td>
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<tr>
<td>Particle size ≥ 1 μm</td>
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</tbody>
</table>

**ZEISS CAPA**

- Correlative Automated Particle Analysis
- Correlated analysis across Light and Electron microscopy in a seamless integrated workflow
- **Automatically relocate critical particles**
- **Automated reporting at the click of a button according to all major industry standards** and customized company standards.
- **Up to 10X faster results versus consecutive individual analysis**

**Particle filters** from cleaning cabinet or other particle extraction methods

**Supported industry standards:** VDA 19.1, ISO 16232, ISO 4406, ISO 4007, DIN 51455*, SAE AS 4059, VDI 2083, NAS 1638

* Available as of 2021